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WHAT IS CLAIMED IS:

- 1. An article of manufacture comprising a macroscopic mounting element capable of being manipulated or observed in a macroscale environment and a nanoscale nanotube assembly attached to said mounting element, whereby said article permits macroscale information to be provided to or obtained from a nanoscale environment.
- 2. The article of claim 1 wherein said mounting element is adapted to support and move said nanotube assembly.
- The article of claim wherein said mounting element is adapted to provide an electrical connection to said nanotube assembly.
 - The article of claim 1 additionally comprising detection means operatively associated with said mounting element for detecting information obtained by said nanotube assembly in said nanoscale environment.
- 5. The article of claim 4 wherein said detection means is selected from the group consisting of electronic, electromechanical and optical means.
 - 6. The article of claim 5 wherein said electromechanical detection means is a piezoelectric deflection system.
 - 7. The article of claim 1 wherein said mounting element is a proximity probe cantilever.
- 20 8. The article of claim 1 wherein said mounting element is a proximity probe tip.
 - 9. The method of claim 7 or 8 wherein said proximity probe is adapted for use in a microscopy system selected from the group consisting of STM, AFM and MFM.
- 25 10. The article of claim 1 wherein said nanoscale nanotube assembly comprises a single nanotube.
 - 11. The article of claim 10 wherein said single nanotube is a carbon nanotube.
 - 12. The article f claim 11 wherein said carbon nanotube is selected fr m single-wall carbon nanotubes and multi-wall carbon nanotubes.

- 13. The article of claim 11 wherein said carbon nanotube is a single-wall carbon nanotube.
- 14. The article of claim 11 wherein said single-wall carbon nanotube has insulating properties.
- 5 15. The article of claim 11 wherein said single-wall carbon nanotube has metallic properties.
 - 16. The article of claim 15 wherein said single-wall carbon nanotube has arm chair (n,n) configuration.
- 17. The article of claim 15 wherein said single-wall carbon nanotube has a 10 (10,10) configuration.
 - 18. The article of claim 11 wherein said carbon nanotube is doped with noncarbon atoms in the fullerene lattice.
 - 19. The article of claim 11 wherein said carbon nanotube contains an endohedrally located species.
- 15 20. The article of claim 19 wherein said endohedrally located species is selected from metals, ions, small molecules and fullerenes.
 - 21. The article of claim 20 wherein said species is a paramagnetic material.
 - 22. The article of claim 20 wherein said species is a ferromagnetic material.
- 23. The article of claim 11 wherein said carbon nanotube is derivitized with a chemical moiety.
 - 24. The article of claim 23 wherein said chemical moiety is bound to said carbon nanotube at a position on the side of said nanotube.
 - 25. The article of claim 23 wherein said chemical moiety is bound to the end cap of said nanotube.
- 25 26. The article of claim 1 wherein said nanotube assembly comprises a plurality of generally parallel nanotubes.
 - 27. The article of claim 26 wherein said nanotubes are carbon nanotubes.
 - 28. The article of claim 26 or 27 wherein said plurality of nanotubes is a bundle having from about 2 t about 10³ individual nanotubes.

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- 29. The article of claim 26 or 27 wherein said plurality of nanotubes is a rope having from about 10³ to 10⁶ individual nanotubes.
- 30. The article of claim 26 or 27, wherein said nanotube assembly comprises a body section and a tip section comprising from about 1 to about 10 individual nanotubes projecting beyond said body section.
- 31. The article of claim 1 wherein said nanotube assembly has a length of from about 20 to 100 times its diameter.
- The article of claim I wherein said nanotube assembly is attached to said mounting element at one end and the other end of said nanotube assembly freely projects from said mounting element.
- 33. The article of claim 1 which is a probe for providing information from a nanoscale environment.
- 34. The article of claim 33 which is a probe adapted for use in a proximity probe microscopy system.
- 15 35. The probe of claim 34 wherein said proximity probe microscopy system is STM.
 - 36. The probe of claim 34 wherein said proximity probe microscopy system is AFM.
- 37. The probe of claim 34 wherein said proximity probe microscopy system is 20 MFM.
 - 38. The article of claim 34 wherein said probe is adapted to image a surface at nanoscale resolution.
 - 39. The article of claim 34 wherein said probe is adapted to measure properties of nanoscale objects.
- 25 40. The article of claim 39 wherein said probe is adapted to measure the elasticity of nanoscale objects.
 - The article f claim 39 wherein said probe is adapted t measure atomic scale friction of nanoscale objects.
- 42. The article of claim 39 wherein said probe is adapted to measure electronic properties f nan scale objects.



- The article of claim 39 wherein said probe is adapted to measure magnetic properties of nanoscale objects.
- 44. The article of claim 39 wherein said probe is adapted to measure electrochemical properties of nanoscale objects.
- 5 45. The article of claim 39 wherein said probe is adapted to measure chemical properties of nanoscale objects.
 - The article of claim 39 wherein said probe is adapted to measure biological properties of nanoscale objects.
- The article of claim 46 wherein said probe is adapted to analyze biomolecules and components thereof.
 - 48. The article of claim 47 wherein said probe is adapted to sequence DNA molecules by recognizing individual base moieties.
 - 49. The article of claim 1 which is a probe for manipulating or modifying a nanoscale object.
- 15 50. The article of claim 49 wherein said probe is adapted to move a nanoscale object.
 - 51. The article of claim 49 wherein said probe is adapted to modify a nanoscale surface by creating a pattern on the surface of said object.
- 52. The article of claim 51 wherein said probe is adapted to perform nanolithography.
 - 53. The article of claim 49 wherein said probe is adapted to chemically modify said nanoscale object.
 - 54. The article of claim 53 wherein said probe contains a chemical moiety attached to its tip to induce said chemical modification.
- 25 55. The article of claim 53 wherein said probe is adapted to emit electrons to induce said chemical modification.
 - 56. The article of claim 53 wherein said probe is adapted to emit electromagnetic radiation to induce said chemical modification.
- 57. The article of claim 54 wherein said chemical moiety is a species that reacts with species on the surface of said nanoscale object.



- 58. The article of claim 54 wherein said chemical moiety is a catalyst for a reaction that takes place on the surface of said nanoscale object.
- 59. The article of claim 1 which is a tool for the fabrication of nanoscale devices.
- The article of claim 1 wherein at least a portion of said nanotube assembly is coated with a material selected from the group consisting of thermosetting polymers, thermoplastic polymers, UV curing polymers, silicon and metals.
- The method of claim 60 wherein said coating also covers at least a portion of said mounting element.
 - 62. The article of claim 1 comprising an array of nanotube assemblies attached to mounting elements.
 - 63. The article of claim 62 wherein said nanotube assemblies are each attached to separate mounting elements.
- 15 64. The article of claim 63 wherein said nanotube assemblies are attached to a common mounting element.
 - 65. A method for making a macroscopically manipulable nanoscale device comprising:

 providing a nanotube-containing material;
- 20 preparing a nanotube assembly having at least one nanotube; and attaching said nanotube assembly to a surface of a mounting element.
 - 66. The method of claim 65 wherein said nanotube is a carbon nanotube.
 - 67. The method of claim 65, further comprising coating a portion of said nanotube assembly with a metal.
- 25 68. The method of claim 65, wherein said step of preparing a nanotube assembly comprises:

 contacting said nanotube-containing material with an adhesive member; and removing said adhesive member from said nanotube-containing material, whereby a plurality of nanotubes are oriented perpendicular to said surface of said nanotube-containing material.

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- The method of claim 65, wherein said step of attaching said nanotube assembly to a surface of a mounting element comprises: translating said mounting element toward said nanotube assembly; contacting said mounting element and said nanotube assembly; and translating said mounting element away from said nanotube assembly.
- 70. The method of claim 65, wherein nanotube assembly and said mounting element are attached by van der Waais forces.
- 71. The method of claim 65, wherein said nanotube assembly and said mounting element are attached by adhesive bonding.
- The method of claim 69 wherein a portion of said mounting element is coated with an adhesive prior to contact with said nanotube assembly.
 - 73. The method of claim 72, wherein said adhesive is an acrylic adhesive.
 - 74. The method of claim 66, wherein said surface of said mounting device is highly
- 15 graphitized carbon.
 - 75. The method of claim 65, further comprising coating the nanotube assembly attached to said mounting element.
 - 76. The method of claim 75, wherein said coating is applied by dipping.
 - 77. The method of claim 75, wherein said coating is applied by vapor phase deposition.
 - 78. The method of claim 75, wherein said coating is selected from the group consisting of cyanoacrylate, methacrylate, Parylene®, polyimide, silicon, silica and metals.
- 79. The method of claim 65 wherein said attaching step is performed under observation using an optical microscope.
 - 80. A method for imaging an object at nanoscale resolution comprising scanning the surface of said object with a proximity probe microscopy apparatus having a pr be tip that comprises a nanoscale nanotube assembly.
- A method for manipulating or modifying nan scale bjects comprising bringing a probe tip comprising a nanoscale nanotube assembly into contract

with or proximity to said nanoscale objects and actuating an interaction between said probe tip and said nanoscale object.

- 82. The method of claim 81 wherein said interaction is by direct physical contact.
- The method of claim 81 wherein said interaction is effected by indirect means selected from the group consisting of electronic, chemical, mechanical, electrochemical, electromechanical, electromagnetic, magnetic and biological.